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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	e200z0h
Core Size	32-Bit Single-Core
Speed	64MHz
Connectivity	CANbus, LINbus, SPI, UART/USART
Peripherals	DMA, POR, PWM, WDT
Number of I/O	80
Program Memory Size	384KB (384K x 8)
Program Memory Type	FLASH
EEPROM Size	64K x 8
RAM Size	36K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 3.6V
Data Converters	A/D 26x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	144-LQFP
Supplier Device Package	144-LQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/spc560p44l5cefbr

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Table 2. SPC560P44Lx, SPC560P50Lx device comparison (continued)

Feature		SPC560P44	SPC560P50
eDMA (enhanced direct memory access) channels		16	
FlexRay		Yes ⁽¹⁾	
FlexCAN (controller area network)		2 ^{(2),(3)}	
Safety port		Yes (via second FlexCAN module)	
FCU (fault collection unit)		Yes	
CTU (cross triggering unit)		Yes	
eTimer		2 (16-bit, 6 channels)	
FlexPWM (pulse-width modulation) channels		8 (capturing on X-channels)	
ADC (analog-to-digital converter)		2 (10-bit, 15-channel ⁽⁴⁾)	
LINFlex		2	
DSPI (deserial serial peripheral interface)		4	
CRC (cyclic redundancy check) unit		Yes	
JTAG controller		Yes	
Nexus port controller (NPC)		Yes (Level 2+)	
Supply	Digital power supply ⁽⁵⁾	3.3 V or 5 V single supply with external transistor	
	Analog power supply	3.3 V or 5 V	
	Internal RC oscillator	16 MHz	
	External crystal oscillator	4–40 MHz	
Packages		LQFP100 LQFP144	
Temperature	Standard ambient temperature	–40 to 125 °C	

1. 32 message buffers, selectable single or dual channel support
2. Each FlexCAN module has 32 message buffers.
3. One FlexCAN module can act as a Safety Port with a bit rate as high as 7.5 Mbit/s.
4. Four channels shared between the two ADCs
5. The different supply voltages vary according to the part number ordered.

SPC560P44Lx, SPC560P50Lx is available in two configurations having different features: full-featured and airbag. [Table 3](#) shows the main differences between the two versions.

Table 3. SPC560P44Lx, SPC560P50Lx device configuration differences

Feature	Full-featured	Airbag
CTU (cross triggering unit)	Yes	No
FlexPWM	Yes	No

The SIU provides the following features:

- Centralized general purpose input output (GPIO) control of as many as 80 input/output pins and 26 analog input-only pads (package dependent)
- All GPIO pins can be independently configured to support pull-up, pull down, or no pull
- Reading and writing to GPIO supported both as individual pins and 16-bit wide ports
- All peripheral pins (except ADC channels) can be alternatively configured as both general purpose input or output pins
- ADC channels support alternative configuration as general purpose inputs
- Direct readback of the pin value is supported on all pins through the SIUL
- Configurable digital input filter that can be applied to some general purpose input pins for noise elimination: as many as 4 internal functions can be multiplexed onto 1 pin

1.5.17 Boot and censorship

Different booting modes are available in the SPC560P44Lx, SPC560P50Lx: booting from internal flash memory and booting via a serial link.

The default booting scheme uses the internal flash memory (an internal pull-down is used to select this mode). Optionally, the user can boot via FlexCAN or LINFlex (using the boot assist module software).

A censorship scheme is provided to protect the content of the flash memory and offer increased security for the entire device.

A password mechanism is designed to grant the legitimate user access to the non-volatile memory.

Boot assist module (BAM)

The BAM is a block of read-only one-time programmed memory and is identical for all SPC560Pxx devices that are based on the e200z0h core. The BAM program is executed every time the device is powered on if the alternate boot mode has been selected by the user.

The BAM provides the following features:

- Serial bootloading via FlexCAN or LINFlex
- Ability to accept a password via the used serial communication channel to grant the legitimate user access to the non-volatile memory

1.5.18 Error correction status module (ECSM)

The ECSM provides a myriad of miscellaneous control functions regarding program-visible information about the platform configuration and revision levels, a reset status register, a software watchdog timer, wakeup control for exiting sleep modes, and information on platform memory errors reported by error-correcting codes and/or generic access error information for certain processor cores.

The Error Correction Status Module supports a number of miscellaneous control functions for the platform. The ECSM includes these features:

- Registers for capturing information on platform memory errors if error-correcting codes (ECC) are implemented
- For test purposes, optional registers to specify the generation of double-bit memory errors are enabled on the SPC560P44Lx, SPC560P50Lx.

block is an integration of several individual Nexus blocks that are selected to provide the development support interface for this device. The NDI block interfaces to the host processor and internal busses to provide development support as per the IEEE-ISTO 5001-2003 Class 2+ standard. The development support provided includes access to the MCU's internal memory map and access to the processor's internal registers during run time.

The Nexus Interface provides the following features:

- Configured via the IEEE 1149.1
- All Nexus port pins operate at V_{DDIO} (no dedicated power supply)
- Nexus 2+ features supported
 - Static debug
 - Watchpoint messaging
 - Ownership trace messaging
 - Program trace messaging
 - Real time read/write of any internally memory mapped resources through JTAG pins
 - Overrun control, which selects whether to stall before Nexus overruns or keep executing and allow overwrite of information
 - Watchpoint triggering, watchpoint triggers program tracing
- Auxiliary Output Port
 - 4 MDO (Message Data Out) pins
 - MCKO (Message Clock Out) pin
 - 2 MSEO (Message Start/End Out) pins
 - $\overline{EVTO}$ (Event Out) pin
- Auxiliary Input Port
 - $\overline{EVTI}$ (Event In) pin

1.5.30 Cyclic redundancy check (CRC)

The CRC computing unit is dedicated to the computation of CRC off-loading the CPU. The CRC module features:

- Support for CRC-16-CCITT (x25 protocol):
 - $x^{16} + x^{12} + x^5 + 1$
- Support for CRC-32 (Ethernet protocol):
 - $x^{32} + x^{26} + x^{23} + x^{22} + x^{16} + x^{12} + x^{11} + x^{10} + x^8 + x^7 + x^5 + x^4 + x^2 + x + 1$
- Zero wait states for each write/read operations to the CRC_CFG and CRC_INP registers at the maximum frequency

1.5.31 IEEE 1149.1 JTAG controller

The JTAG controller (JTAGC) block provides the means to test chip functionality and connectivity while remaining transparent to system logic when not in test mode. All data input to and output from the JTAGC block is communicated in serial format. The JTAGC block is compliant with the IEEE standard.

2 Package pinouts and signal descriptions

2.1 Package pinouts

The LQFP pinouts are shown in the following figures.

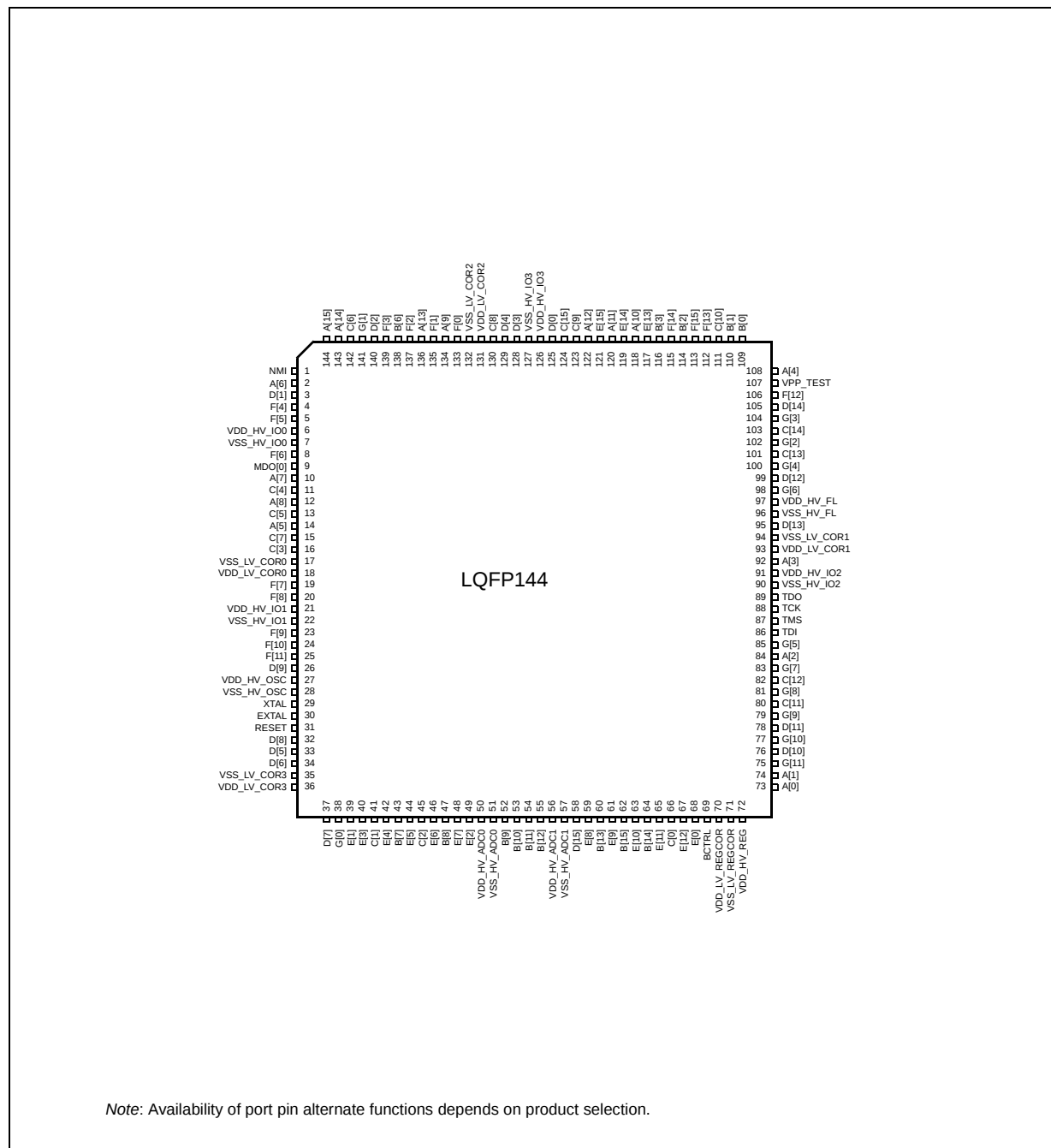


Figure 2. 144-pin LQFP pinout – Full featured configuration (top view)

Table 7. Pin muxing

Port pin	Pad configuration register (PCR)	Alternate function ⁽¹⁾ , (2)	Functions	Peripheral ⁽³⁾	I/O direction ⁽⁴⁾	Pad speed ⁽⁵⁾		Pin No.	
						SRC = 0	SRC = 1	100-pin	144-pin
Port A (16-bit)									
A[0]	PCR[0]	ALT0 ALT1 ALT2 ALT3 —	GPIO[0] ETC[0] SCK F[0] EIRQ[0]	SIUL eTimer_0 DSPI_2 FCU_0 SIUL	I/O I/O O O I	Slow	Medium	51	73
A[1]	PCR[1]	ALT0 ALT1 ALT2 ALT3 —	GPIO[1] ETC[1] SOUT F[1] EIRQ[1]	SIUL eTimer_0 DSPI_2 FCU_0 SIUL	I/O I/O O O I	Slow	Medium	52	74
A[2] ⁽⁶⁾	PCR[2]	ALT0 ALT1 ALT2 ALT3 — — —	GPIO[2] ETC[2] — A[3] SIN ABS[0] EIRQ[2]	SIUL eTimer_0 — FlexPWM_0 DSPI_2 MC_RGM SIUL	I/O I/O — O I I I	Slow	Medium	57	84
A[3] ⁽⁶⁾	PCR[3]	ALT0 ALT1 ALT2 ALT3 — —	GPIO[3] ETC[3] CS0 B[3] ABS[2] EIRQ[3]	SIUL eTimer_0 DSPI_2 FlexPWM_0 MC_RGM SIUL	I/O I/O I/O O I I	Slow	Medium	64	92
A[4] ⁽⁶⁾	PCR[4]	ALT0 ALT1 ALT2 ALT3 — —	GPIO[4] ETC[0] CS1 ETC[4] FAB EIRQ[4]	SIUL eTimer_1 DSPI_2 eTimer_0 MC_RGM SIUL	I/O I/O O I/O I I	Slow	Medium	75	108
A[5]	PCR[5]	ALT0 ALT1 ALT2 ALT3 —	GPIO[5] CS0 ETC[5] CS7 EIRQ[5]	SIUL DSPI_1 eTimer_1 DSPI_0 SIUL	I/O I/O I/O O I	Slow	Medium	8	14
A[6]	PCR[6]	ALT0 ALT1 ALT2 ALT3 —	GPIO[6] SCK — — EIRQ[6]	SIUL DSPI_1 — — SIUL	I/O I/O — — I	Slow	Medium	2	2

Table 7. Pin muxing (continued)

Port pin	Pad configuration register (PCR)	Alternate function ⁽¹⁾ , (2)	Functions	Peripheral ⁽³⁾	I/O direction ⁽⁴⁾	Pad speed ⁽⁵⁾		Pin No.	
						SRC = 0	SRC = 1	100-pin	144-pin
A[14]	PCR[14]	ALT0 ALT1 ALT2 ALT3 —	GPIO[14] TXD ETC[4] — EIRQ[13]	SIUL Safety Port_0 eTimer_1 — SIUL	I/O O I/O — I	Slow	Medium	99	143
A[15]	PCR[15]	ALT0 ALT1 ALT2 ALT3 — —	GPIO[15] — ETC[5] — RXD EIRQ[14]	SIUL — eTimer_1 — Safety Port_0 SIUL	I/O — I/O — I I	Slow	Medium	100	144
Port B (16-bit)									
B[0]	PCR[16]	ALT0 ALT1 ALT2 ALT3 —	GPIO[16] TXD ETC[2] DEBUG[0] EIRQ[15]	SIUL FlexCAN_0 eTimer_1 SSCM SIUL	I/O O I/O — I	Slow	Medium	76	109
B[1]	PCR[17]	ALT0 ALT1 ALT2 ALT3 — —	GPIO[17] — ETC[3] DEBUG[1] RXD EIRQ[16]	SIUL — eTimer_1 SSCM FlexCAN_0 SIUL	I/O — I/O — I I	Slow	Medium	77	110
B[2]	PCR[18]	ALT0 ALT1 ALT2 ALT3 —	GPIO[18] TXD — DEBUG[2] EIRQ[17]	SIUL LIN_0 — SSCM SIUL	I/O O — — I	Slow	Medium	79	114
B[3]	PCR[19]	ALT0 ALT1 ALT2 ALT3 —	GPIO[19] — — DEBUG[3] RXD	SIUL — — SSCM LIN_0	I/O — — — I	Slow	Medium	80	116
B[6]	PCR[22]	ALT0 ALT1 ALT2 ALT3 —	GPIO[22] CLKOUT CS2 — EIRQ[18]	SIUL MC_CGL DSPI_2 — SIUL	I/O O O — I	Slow	Medium	96	138

Table 7. Pin muxing (continued)

Port pin	Pad configuration register (PCR)	Alternate function ⁽¹⁾ , (2)	Functions	Peripheral ⁽³⁾	I/O direction ⁽⁴⁾	Pad speed ⁽⁵⁾		Pin No.	
						SRC = 0	SRC = 1	100-pin	144-pin
C[13]	PCR[45]	ALT0 ALT1 ALT2 ALT3 — —	GPIO[45] ETC[1] — — EXT_IN EXT_SYNC	SIUL eTimer_1 — — CTU_0 FlexPWM_0	I/O I/O — — I I	Slow	Medium	71	101
C[14]	PCR[46]	ALT0 ALT1 ALT2 ALT3	GPIO[46] ETC[2] EXT_TGR —	SIUL eTimer_1 CTU_0 —	I/O I/O O —	Slow	Medium	72	103
C[15]	PCR[47]	ALT0 ALT1 ALT2 ALT3 — —	GPIO[47] CA_TR_EN ETC[0] A[1] EXT_IN EXT_SYNC	SIUL FlexRay_0 eTimer_1 FlexPWM_0 CTU_0 FlexPWM_0	I/O O I/O O I I	Slow	Symmetric	85	124
Port D (16-bit)									
D[0]	PCR[48]	ALT0 ALT1 ALT2 ALT3	GPIO[48] CA_TX ETC[1] B[1]	SIUL FlexRay_0 eTimer_1 FlexPWM_0	I/O O I/O O	Slow	Symmetric	86	125
D[1]	PCR[49]	ALT0 ALT1 ALT2 ALT3 —	GPIO[49] — ETC[2] EXT_TRG CA_RX	SIUL — eTimer_1 CTU_0 FlexRay_0	I/O — I/O O I	Slow	Medium	3	3
D[2]	PCR[50]	ALT0 ALT1 ALT2 ALT3 —	GPIO[50] — ETC[3] X[3] CB_RX	SIUL — eTimer_1 FlexPWM_0 FlexRay_0	I/O — I/O I/O I	Slow	Medium	97	140
D[3]	PCR[51]	ALT0 ALT1 ALT2 ALT3	GPIO[51] CB_TX ETC[4] A[3]	SIUL FlexRay_0 eTimer_1 FlexPWM_0	I/O O I/O O	Slow	Symmetric	89	128
D[4]	PCR[52]	ALT0 ALT1 ALT2 ALT3	GPIO[52] CB_TR_EN ETC[5] B[3]	SIUL FlexRay_0 eTimer_1 FlexPWM_0	I/O O I/O O	Slow	Symmetric	90	129

Table 7. Pin muxing (continued)

Port pin	Pad configuration register (PCR)	Alternate function ⁽¹⁾ , (2)	Functions	Peripheral ⁽³⁾	I/O direction ⁽⁴⁾	Pad speed ⁽⁵⁾		Pin No.	
						SRC = 0	SRC = 1	100-pin	144-pin
D[5]	PCR[53]	ALT0 ALT1 ALT2 ALT3	GPIO[53] CS3 F[0] SOUT	SIUL DSPI_0 FCU_0 DSPI_3	I/O O O O	Slow	Medium	22	33
D[6]	PCR[54]	ALT0 ALT1 ALT2 ALT3 —	GPIO[54] CS2 SCK — FAULT[1]	SIUL DSPI_0 DSPI_3 — FlexPWM_0	I/O O I/O — I	Slow	Medium	23	34
D[7]	PCR[55]	ALT0 ALT1 ALT2 ALT3 —	GPIO[55] CS3 F[1] CS4 SIN	SIUL DSPI_1 FCU_0 DSPI_0 DSPI_3	I/O O O O I	Slow	Medium	26	37
D[8]	PCR[56]	ALT0 ALT1 ALT2 ALT3 —	GPIO[56] CS2 — CS5 FAULT[3]	SIUL DSPI_1 — DSPI_0 FlexPWM_0	I/O O — O I	Slow	Medium	21	32
D[9]	PCR[57]	ALT0 ALT1 ALT2 ALT3	GPIO[57] X[0] TXD —	SIUL FlexPWM_0 LIN_1 —	I/O I/O O —	Slow	Medium	15	26
D[10]	PCR[58]	ALT0 ALT1 ALT2 ALT3	GPIO[58] A[0] CS0 —	SIUL FlexPWM_0 DSPI_3 —	I/O O I/O —	Slow	Medium	53	76
D[11]	PCR[59]	ALT0 ALT1 ALT2 ALT3	GPIO[59] B[0] CS1 SCK	SIUL FlexPWM_0 DSPI_3 DSPI_3	I/O O O I/O	Slow	Medium	54	78
D[12]	PCR[60]	ALT0 ALT1 ALT2 ALT3 —	GPIO[60] X[1] — — RXD	SIUL FlexPWM_0 — — LIN_1	I/O I/O — — I	Slow	Medium	70	99
D[13]	PCR[61]	ALT0 ALT1 ALT2 ALT3	GPIO[61] A[1] CS2 SOUT	SIUL FlexPWM_0 DSPI_3 DSPI_3	I/O O O O	Slow	Medium	67	95

Table 7. Pin muxing (continued)

Port pin	Pad configuration register (PCR)	Alternate function ⁽¹⁾ , (2)	Functions	Peripheral ⁽³⁾	I/O direction ⁽⁴⁾	Pad speed ⁽⁵⁾		Pin No.	
						SRC = 0	SRC = 1	100-pin	144-pin
D[14]	PCR[62]	ALT0 ALT1 ALT2 ALT3 —	GPIO[62] B[1] CS3 — SIN	SIUL FlexPWM_0 DSPI_3 — DSPI_3	I/O O O — I	Slow	Medium	73	105
D[15]	PCR[63]	ALT0 ALT1 ALT2 ALT3 —	GPIO[63] — — — AN[4]	SIUL — — — ADC_1	Input only	—	—	41	58
Port E(16-bit)									
E[0]	PCR[64]	ALT0 ALT1 ALT2 ALT3 —	GPIO[64] — — — AN[5]	SIUL — — — ADC_1	Input only	—	—	46	68
E[1]	PCR[65]	ALT0 ALT1 ALT2 ALT3 —	GPIO[65] — — — AN[4]	SIUL — — — ADC_0	Input only	—	—	27	39
E[2]	PCR[66]	ALT0 ALT1 ALT2 ALT3 —	GPIO[66] — — — AN[5]	SIUL — — — ADC_0	Input only	—	—	32	49
E[3]	PCR[67]	ALT0 ALT1 ALT2 ALT3 —	GPIO[67] — — — AN[6]	SIUL — — — ADC_0	Input only	—	—	—	40
E[4]	PCR[68]	ALT0 ALT1 ALT2 ALT3 —	GPIO[68] — — — AN[7]	SIUL — — — ADC_0	Input only	—	—	—	42

Table 7. Pin muxing (continued)

Port pin	Pad configuration register (PCR)	Alternate function ⁽¹⁾ , (2)	Functions	Peripheral ⁽³⁾	I/O direction ⁽⁴⁾	Pad speed ⁽⁵⁾		Pin No.	
						SRC = 0	SRC = 1	100-pin	144-pin
E[5]	PCR[69]	ALT0 ALT1 ALT2 ALT3 —	GPIO[69] — — — AN[8]	SIUL — — — ADC_0	Input only	—	—	—	44
E[6]	PCR[70]	ALT0 ALT1 ALT2 ALT3 —	GPIO[70] — — — AN[9]	SIUL — — — ADC_0	Input only	—	—	—	46
E[7]	PCR[71]	ALT0 ALT1 ALT2 ALT3 —	GPIO[71] — — — AN[10]	SIUL — — — ADC_0	Input only	—	—	—	48
E[8]	PCR[72]	ALT0 ALT1 ALT2 ALT3 —	GPIO[72] — — — AN[6]	SIUL — — — ADC_1	Input only	—	—	—	59
E[9]	PCR[73]	ALT0 ALT1 ALT2 ALT3 —	GPIO[73] — — — AN[7]	SIUL — — — ADC_1	Input only	—	—	—	61
E[10]	PCR[74]	ALT0 ALT1 ALT2 ALT3 —	GPIO[74] — — — AN[8]	SIUL — — — ADC_1	Input only	—	—	—	63
E[11]	PCR[75]	ALT0 ALT1 ALT2 ALT3 —	GPIO[75] — — — AN[9]	SIUL — — — ADC_1	Input only	—	—	—	65
E[12]	PCR[76]	ALT0 ALT1 ALT2 ALT3 —	GPIO[76] — — — AN[10]	SIUL — — — ADC_1	Input only	—	—	—	67

Table 7. Pin muxing (continued)

Port pin	Pad configuration register (PCR)	Alternate function ⁽¹⁾ , (2)	Functions	Peripheral ⁽³⁾	I/O direction ⁽⁴⁾	Pad speed ⁽⁵⁾		Pin No.	
						SRC = 0	SRC = 1	100-pin	144-pin
F[14]	PCR[94]	ALT0 ALT1 ALT2 ALT3	GPIO[94] TXD — —	SIUL LIN_1 — —	I/O O — —	Slow	Medium	—	115
F[15]	PCR[95]	ALT0 ALT1 ALT2 ALT3 —	GPIO[95] — — — RXD	SIUL — — — LIN_1	I/O — — — I	Slow	Medium	—	113
Port G (12-bit)									
G[0]	PCR[96]	ALT0 ALT1 ALT2 ALT3 —	GPIO[96] F[0] — — EIRQ[30]	SIUL FCU_0 — — SIUL	I/O O — — I	Slow	Medium	—	38
G[1]	PCR[97]	ALT0 ALT1 ALT2 ALT3 —	GPIO[97] F[1] — — EIRQ[31]	SIUL FCU_0 — — SIUL	I/O O — — I	Slow	Medium	—	141
G[2]	PCR[98]	ALT0 ALT1 ALT2 ALT3	GPIO[98] X[2] — —	SIUL FlexPWM_0 — —	I/O I/O — —	Slow	Medium	—	102
G[3]	PCR[99]	ALT0 ALT1 ALT2 ALT3	GPIO[99] A[2] — —	SIUL FlexPWM_0 — —	I/O O — —	Slow	Medium	—	104
G[4]	PCR[100]	ALT0 ALT1 ALT2 ALT3	GPIO[100] B[2] — —	SIUL FlexPWM_0 — —	I/O O — —	Slow	Medium	—	100
G[5]	PCR[101]	ALT0 ALT1 ALT2 ALT3	GPIO[101] X[3] — —	SIUL FlexPWM_0 — —	I/O I/O — —	Slow	Medium	—	85
G[6]	PCR[102]	ALT0 ALT1 ALT2 ALT3	GPIO[102] A[3] — —	SIUL FlexPWM_0 — —	I/O O — —	Slow	Medium	—	98

common usage: the value determined on a single layer board and the value obtained on a board with two planes. For packages such as the PBGA, these values can be different by a factor of two. Which value is closer to the application depends on the power dissipated by other components on the board. The value obtained on a single layer board is appropriate for the tightly packed printed circuit board. The value obtained on the board with the internal planes is usually appropriate if the board has low power dissipation and the components are well separated.

When a heat sink is used, the thermal resistance is expressed in [Equation 2](#) as the sum of a junction to case thermal resistance and a case to ambient thermal resistance:

Equation 2 $R_{\theta JA} = R_{\theta JC} + R_{\theta CA}$

where:

$R_{\theta JA}$ = junction to ambient thermal resistance (°C/W)

$R_{\theta JC}$ = junction to case thermal resistance (°C/W)

$R_{\theta CA}$ = case to ambient thermal resistance (°C/W)

$R_{\theta JC}$ is device related and cannot be influenced by the user. The user controls the thermal environment to change the case to ambient thermal resistance, $R_{\theta CA}$. For instance, the user can change the size of the heat sink, the air flow around the device, the interface material, the mounting arrangement on printed circuit board, or change the thermal dissipation on the printed circuit board surrounding the device.

To determine the junction temperature of the device in the application when heat sinks are not used, the Thermal Characterization Parameter (Ψ_{JT}) can be used to determine the junction temperature with a measurement of the temperature at the top center of the package case using [Equation 3](#):

Equation 3 $T_J = T_T + (\Psi_{JT} \times P_D)$

where:

T_T = thermocouple temperature on top of the package (°C)

Ψ_{JT} = thermal characterization parameter (°C/W)

P_D = power dissipation in the package (W)

The thermal characterization parameter is measured per JESD51-2 specification using a 40 gauge type T thermocouple epoxied to the top center of the package case. The thermocouple should be positioned so that the thermocouple junction rests on the package. A small amount of epoxy is placed over the thermocouple junction and over about 1 mm of wire extending from the junction. The thermocouple wire is placed flat against the package case to avoid measurement errors caused by cooling effects of the thermocouple wire.

References:

Semiconductor Equipment and Materials International
3081 Zanker Road
San Jose, CA 95134 U.S.A.
(408) 943-6900

MIL-SPEC and EIA/JESD (JEDEC) specifications are available from Global Engineering Documents at 800-854-7179 or 303-397-7956.

JEDEC specifications are available on the WEB at <http://www.jedec.org>.

3.15 Flash memory electrical characteristics

Table 34. Program and erase specifications

Symbol	C	Parameter	Value				Unit
			Min	Typical ⁽¹⁾	Initial max ⁽²⁾	Max ⁽³⁾	
T _{dwprogram}	P	Double Word (64 bits) Program Time ⁽⁴⁾	—	22	50	500	μs
T _{BKPRG}	P	Bank Program (512 KB) ⁽⁴⁾⁽⁵⁾	—	1.45	1.65	33	s
	P	Bank Program (64 KB) ⁽⁴⁾⁽⁵⁾	—	0.18	0.21	4.10	s
T _{16kpperase}	P	16 KB Block Pre-program and Erase Time	—	300	500	5000	ms
T _{32kpperase}	P	32 KB Block Pre-program and Erase Time	—	400	600	5000	ms
T _{128kpperase}	P	128 KB Block Pre-program and Erase Time	—	800	1300	7500	ms

1. Typical program and erase times assume nominal supply values and operation at 25 °C. All times are subject to change pending device characterization.
2. Initial factory condition: < 100 program/erase cycles, 25 °C, typical supply voltage.
3. The maximum program and erase times occur after the specified number of program/erase cycles. These maximum values are characterized but not guaranteed.
4. Actual hardware programming times. This does not include software overhead.
5. Typical Bank programming time assumes that all cells are programmed in a single pulse. In reality some cells will require more than one pulse, adding a small overhead to total bank programming time (see Initial Max column).

Table 35. Flash memory module life

Symbol	C	Parameter	Conditions	Value		Unit
				Min	Typ	
P/E	C	Number of program/erase cycles per block for 16 KB blocks over the operating temperature range (T _J)	—	100000	—	cycles
P/E	C	Number of program/erase cycles per block for 32 KB blocks over the operating temperature range (T _J)	—	10000	100000	cycles
P/E	C	Number of program/erase cycles per block for 128 KB blocks over the operating temperature range (T _J)	—	1000	100000	cycles
Retention	C	Minimum data retention at 85 °C average ambient temperature ⁽¹⁾	Blocks with 0–1000 P/E cycles	20	—	years
			Blocks with 10000 P/E cycles	10	—	years
			Blocks with 100000 P/E cycles	5	—	years

1. Ambient temperature averaged over duration of application, not to exceed recommended product operating temperature range.

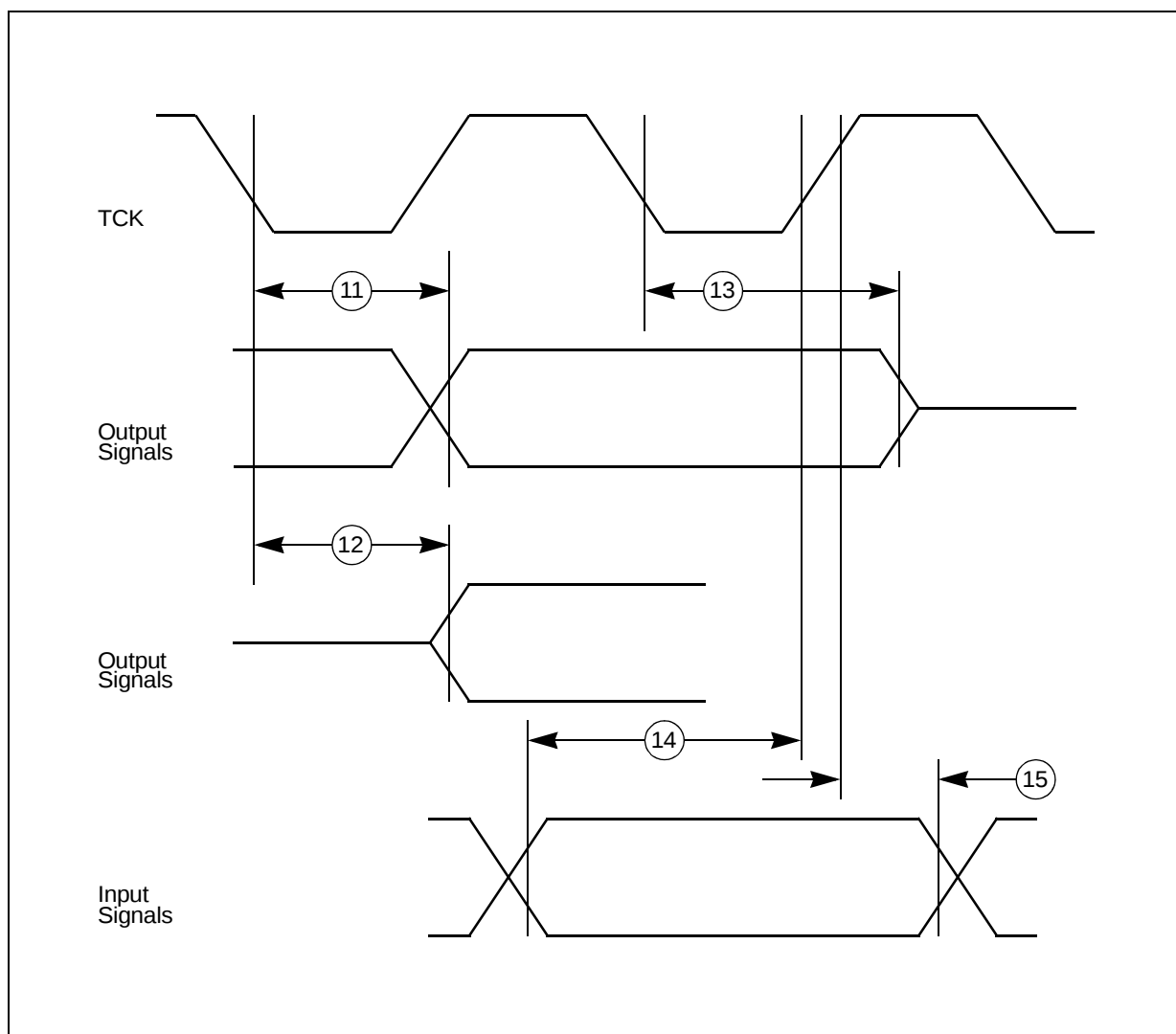


Figure 24. JTAG boundary scan timing

3.17.3 Nexus timing

Table 40. Nexus debug port timing⁽¹⁾

No.	Symbol		C	Parameter	Value			Unit
					Min	Typ	Max	
1	t_{MCYC}	CC	D	MCKO cycle time	32	—	—	ns
2	t_{MDOV}	CC	D	MCKO low to MDO data valid ⁽²⁾	—	—	6	ns
3	t_{MSEOV}	CC	D	MCKO low to $\overline{MSEO}$ data valid ⁽²⁾	—	—	6	ns
4	$t_{EVT OV}$	CC	D	MCKO low to $\overline{EVTO}$ data valid ⁽²⁾	—	—	6	ns
5	t_{TCYC}	CC	D	TCK cycle time	64 ⁽³⁾	—	—	ns

Table 42. DSPI timing⁽¹⁾ (continued)

No.	Symbol		C	Parameter	Conditions	Value		Unit
						Min	Max	
11	t _{SUO}	CC	D	Data valid (after SCK edge)	Master (MTFE = 0)	—	12	ns
					Slave	—	36	
					Master (MTFE = 1, CPHA = 0)	—	12	
					Master (MTFE = 1, CPHA = 1)	—	12	
12	t _{HO}	CC	D	Data hold time for outputs	Master (MTFE = 0)	–2	—	ns
					Slave	6	—	
					Master (MTFE = 1, CPHA = 0)	6	—	
					Master (MTFE = 1, CPHA = 1)	–2	—	

1. All timing is provided with 50 pF capacitance on output, 1 ns transition time on input signal.

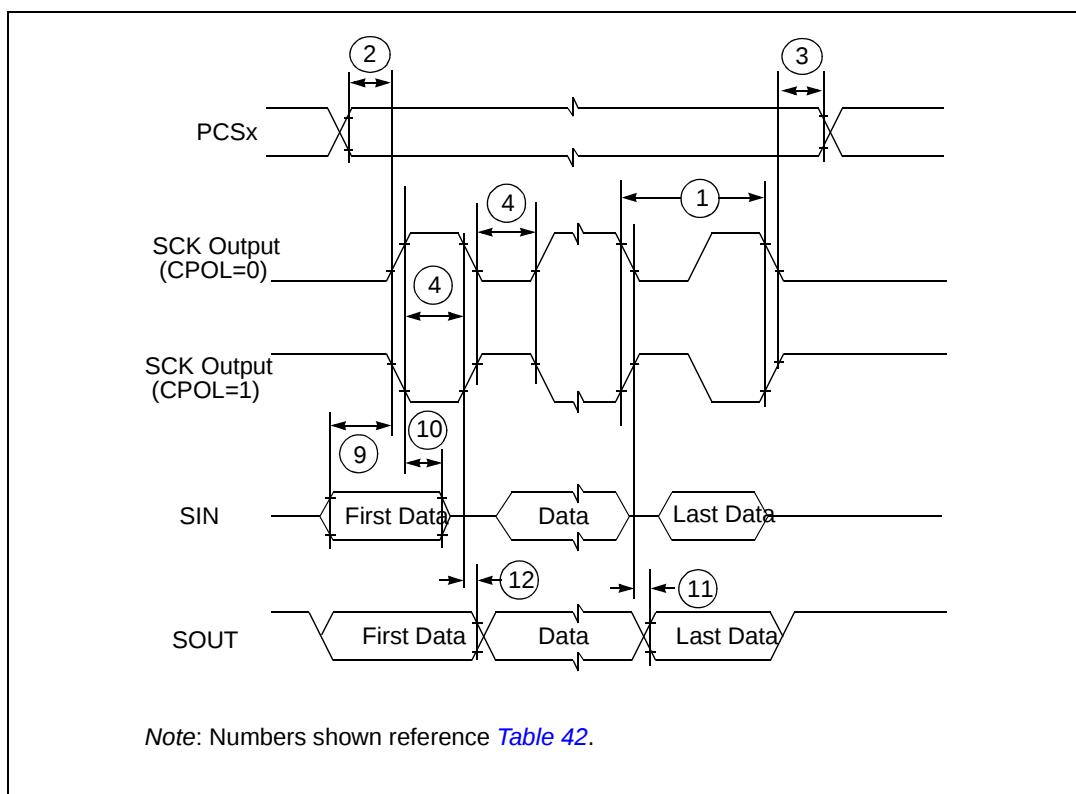


Figure 29. DSPI classic SPI timing – Master, CPHA = 0

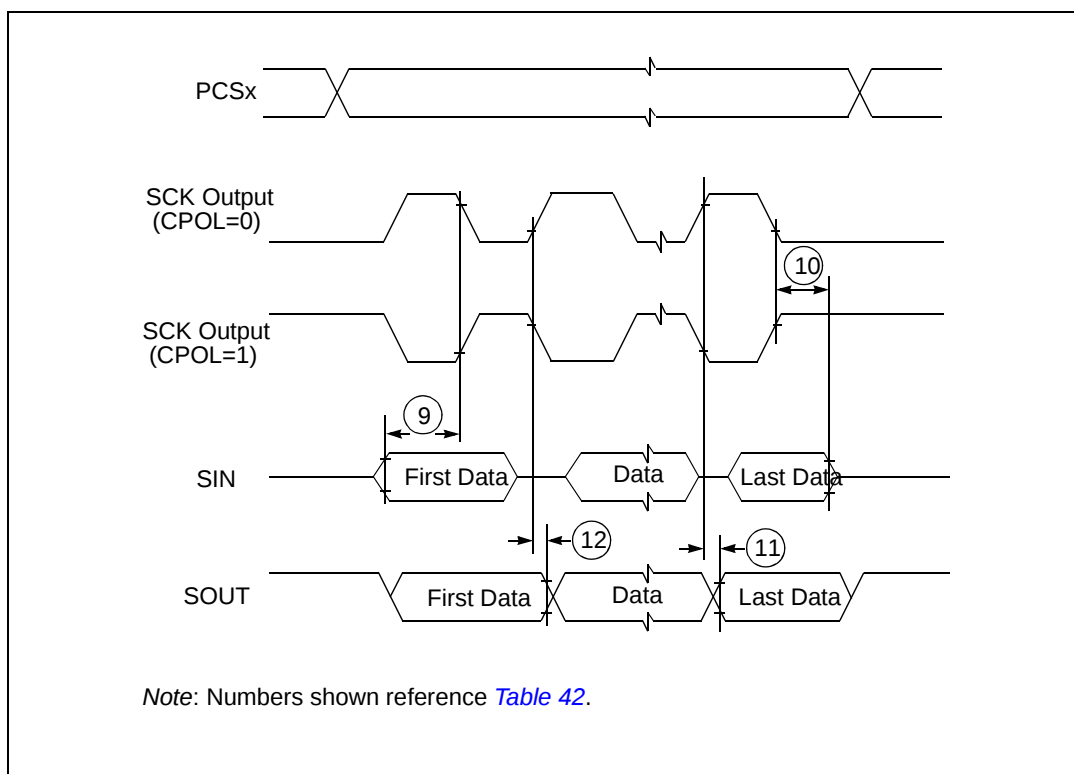


Figure 30. DSPI classic SPI timing – Master, CPHA = 1

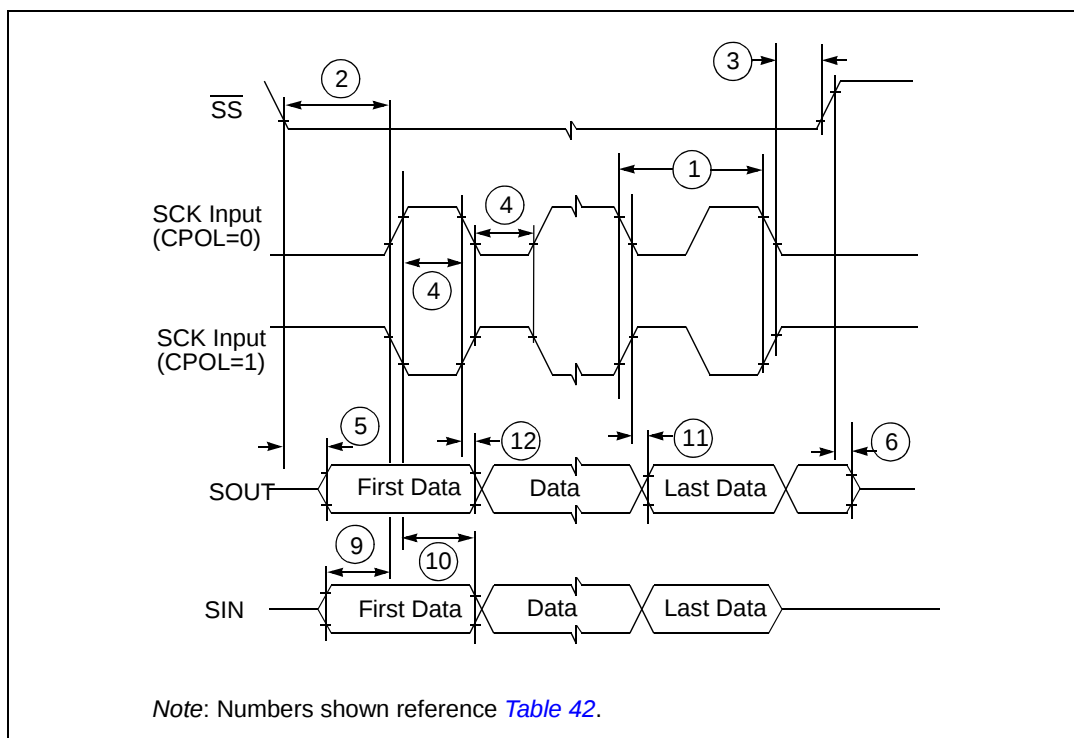


Figure 31. DSPI classic SPI timing – Slave, CPHA = 0

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